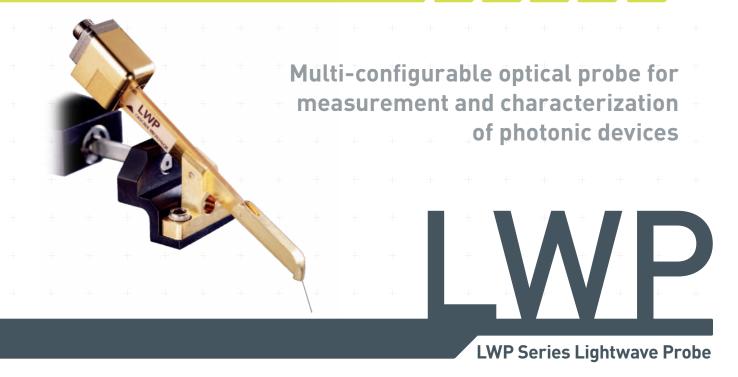
Cascade Microtech, Inc.

SPECIFICATION SHEET



The LWP series of lightwave probes enable optical measurements for on-wafer and hybrid photonics devices. It features user-replaceable fiber pigtails allowing the probe to be optimized for a variety of light delivery and light collection applications including the characterization of topside illuminated photodiodes, Vertical Cavity Surface Emitting Lasers (VCSELs), hybrid transmitters and receivers, and LEDs.

The LWP probe can illuminate and collect optical signals used in the characterization of a variety of photonic devices. When combined with Cascade Microtech's probe stations and RF/DC probes, the LWP probe can provide modulation, spectral, time domain and low-level DC/CV measurements. The choice of field-replaceable fiber pigtail depends on the required illumination pattern or collection efficiency. The fiber pigtails are available as single-mode or multi-mode with either a lensed or cleaved end face. The lensed fiber pigtails provide high numerical aperture (NA) illumination and collect light with extremely low back-reflection. The lensed single-mode fiber can provide an illumination area as small as $5 \, \mu m$. The multi-mode pigtails are well suited for high-efficiency collection of light.

FEATURES

Field interchangeable fiber-type

Optimized for Cascade Microtech probe stations

Patented contact protection design

Fiber-types optimized for a variety of applications

Standard FC type fiber-optic connector

BENEFITS

Brings test equipment capability to the wafer and substrate level

Enables fast, accurate, and repeatable measurements

On-wafer capability eliminates need to dice wafer before test and eliminates electrical parasitics for at-speed testing

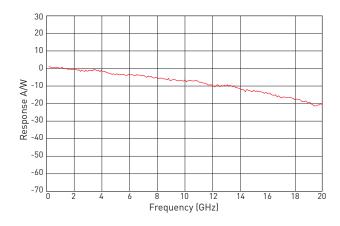
Makes wafer mapping and visual display of key parameters possible

Standard FC type fiber-optic connector

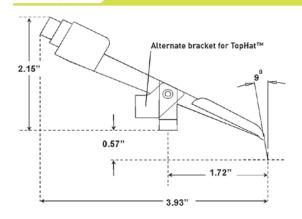
SPECIFICATIONS

Fiber Type	Minimum Illumination	Wavelength	Numeric Aperture	Insertion Loss
	Diameter			
Cleaved single-mode (CLV-SM)	25 μm	1300 nm, 1550 nm	0.13	0.5 dB
Cleaved multi-mode (CLV-MM)	100 µm	850 nm – 1550 nm	0.28	0.5 dB
Lensed single-mode (LEN-SM)	5 μm	1300 nm, 1550 nm	NA	0.5 dB
Lensed single-mode (LEN-MM)	50 μm	850 nm – 1550 nm	NA	0.5 dB

Responsivity measurement of an 80 μm photodiode using the LWP series lightwave probe and the Agilent Technologies 83420A Lightwave Test Set



DIMENSIONS



CREETING INFORMATION

PART NUMBERS

	Probe* with Fiber		Replacement Fibers	
	Cleaved Fiber	Lensed Fiber	Cleaved Fiber	Lensed Fiber
Single mode	LWP-CLV-SM	LWP-LEN-SM	FT-CLV-SM	FT-LEN-SM
Multi mode	LWP-CLV-MM	LWP-LEN-MM	FT-CLV-MM	FT-LEN-MM

^{*}Probe orders include:

Two eyepiece filters for safe viewing of CDRH Class-1 laser sources for wavelengths of 800 nm -1550 nm. Alternate mounting bracket for use with Summit $^{\text{TM}}$ series probe stations (AP/M models with MicroChamber $^{\text{@}}$).

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LWP-SS-0110

